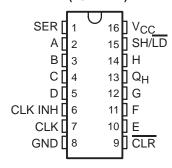
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- Controlled Baseline
  - One Assembly/Test Site, One Fabrication Site
- Enhanced Diminishing Manufacturing Sources (DMS) Support
- Enhanced Product-Change Notification
- Qualification Pedigree<sup>†</sup>
- Wide Operating Voltage Range of 2 V to 6 V
- Outputs Can Drive Up To 10 LSTTL Loads
- Low Power Consumption, 80-μA Max I<sub>CC</sub>
- Typical t<sub>pd</sub> = 13 ns

† Component qualification in accordance with JEDEC and industry standards to ensure reliable operation over an extended temperature range. This includes, but is not limited to, Highly Accelerated Stress Test (HAST) or biased 85/85, temperature cycle, autoclave or unbiased HAST, electromigration, bond intermetallic life, and mold compound life. Such qualification testing should not be viewed as justifying use of this component beyond specified performance and environmental limits.

- ±4-mA Output Drive at 5 V
- Low Input Current of 1 μA Max
- Synchronous Load
- Direct Overriding Clear
- Parallel-to-Serial Conversion

#### D OR PW PACKAGE (TOP VIEW)



#### description/ordering information

This parallel-in or serial-in, serial-out register features gated clock (CLK, CLK INH) inputs and an overriding clear (CLR) input. The parallel-in or serial-in modes are established by the shift/load (SH/LD) input. When high, SH/LD enables the serial (SER) data input and couples the eight flip-flops for serial shifting with each clock (CLK) pulse. When low, the parallel (broadside) data inputs are enabled, and synchronous loading occurs on the next clock pulse. During parallel loading, serial data flow is inhibited. Clocking is accomplished on the low-to-high-level edge of CLK through a 2-input positive-NOR gate, permitting one input to be used as a clock-enable or clock-inhibit function. Holding either CLK or CLK INH high inhibits clocking; holding either low enables the other clock input. This allows the system clock to be free running, and the register can be stopped on command with the other clock input. CLK INH should be changed to the high level only when CLK is high. CLR overrides all other inputs, including CLK, and resets all flip-flops to zero.

#### **ORDERING INFORMATION**

TA	PACKAG	GE‡	ORDERABLE PART NUMBER	TOP-SIDE MARKING
-40°C to 85°C	SOIC - D	Tape and reel	SN74HC166AIDREP	SHC166IEP
-40 C to 65 C	TSSOP - PW	Tape and reel	SN74HC166AIPWREP§	SHC166IEP

<sup>‡</sup> Package drawings, standard packing quantities, thermal data, symbolization, and PCB design guidelines are available at www.ti.com/sc/package.



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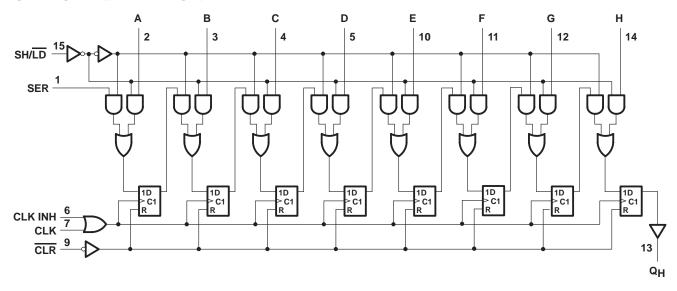
<sup>§</sup> Product Preview

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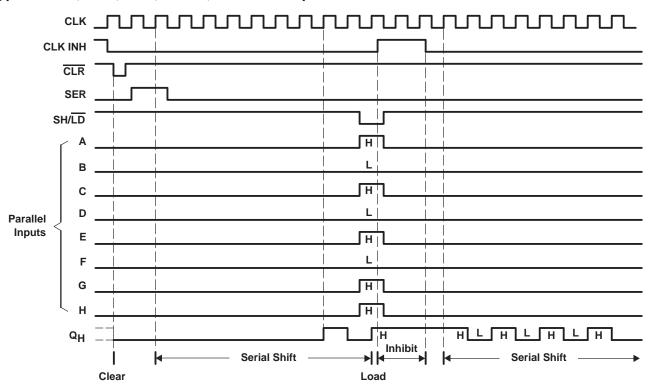
#### **FUNCTION TABLE**

		INIT	LITC			C	UTPUT	S
		INP	UTS			INTE	RNAL	
CLR	SH/LD	CLK INH	CLK	SER	PARALLEL AH	Q <sub>A</sub>	QB	QH
L	Х	Χ	Χ	Χ	Χ	L	L	L
Н	Χ	L	L	Χ	Χ	Q <sub>A0</sub>	$Q_{B0}$	Q <sub>H0</sub>
Н	L	L	$\uparrow$	Χ	ah	а	b	h
Н	Н	L	$\uparrow$	Н	X	Н	$Q_{An}$	QGn
Н	Н	L	$\uparrow$	L	Χ	L	$Q_{An}$	$Q_{Gn}$
Н	Χ	Н	$\uparrow$	X	X	$Q_{A0}$	$Q_{B0}$	Q <sub>H0</sub>

## logic diagram (positive logic)



#### typical clear, shift, load, inhibit, and shift sequence



### absolute maximum ratings over operating free-air temperature range (unless otherwise noted)†

Supply voltage range, V <sub>CC</sub>	0.5 V to 7 V
Input clamp current, $I_{IK}$ ( $V_I < 0$ or $V_I > V_{CC}$ ) (see Note 1)	±20 mA
Output clamp current, I <sub>OK</sub> (V <sub>O</sub> < 0 or V <sub>O</sub> > V <sub>CC</sub> ) (see Note 1)	±20 mA
Continuous output current, $I_O$ ( $V_O = 0$ to $V_{CC}$ )	±25 mA
Continuous current through V <sub>CC</sub> or GND	±50 mA
Package thermal impedance, θ <sub>JA</sub> (see Note 2): D package	73°C/W
PW package	108°C/W
Storage temperature range, T <sub>stg</sub>	–65°C to 150°C

<sup>†</sup> Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTES: 1. The input and output voltage ratings may be exceeded if the input and output current ratings are observed.

2. The package thermal impedance is calculated in accordance with JESD 51-7.



## SN74HC166A-EP 8-BIT PARALLEL-LOAD SHIFT REGISTER

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#### recommended operating conditions (see Note 3)

			MIN	NOM	MAX	UNIT
Vcc	Supply voltage		2	5	6	V
		V <sub>CC</sub> = 2 V	1.5			
ViH	High-level input voltage	V <sub>CC</sub> = 4.5 V	3.15			V
		V <sub>CC</sub> = 6 V	4.2			
		V <sub>CC</sub> = 2 V			0.5	
VIL	Low-level input voltage	V <sub>CC</sub> = 4.5 V			1.35	V
		V <sub>CC</sub> = 6 V			1.8	
٧ <sub>I</sub>	Input voltage		0		VCC	V
Vo	Output voltage		0		VCC	V
		V <sub>CC</sub> = 2 V			1000	
Δt/Δν†	Input transition rise/fall time	V <sub>CC</sub> = 4.5 V			500	ns
		V <sub>CC</sub> = 6 V			400	
TA	Operating free-air temperature		-40		85	°C

<sup>†</sup> If this device is used in the threshold region (from  $V_{IL}$ max = 0.5 V to  $V_{IH}$ min = 1.5 V), there is a potential to go into the wrong state from induced grounding, causing double clocking. Operating with the inputs at  $t_t$  = 1000 ns and  $V_{CC}$  = 2 V does not damage the device; however, functionally, the CLK inputs are not ensured while in the shift, count, or toggle operating modes.

## electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

	TEST CONDITIONS		.,	Т	A = 25°C	;			
PARAMETER	TEST COND	OTTIONS	VCC	MIN	TYP	MAX	MIN	MAX	UNIT
			2 V	1.9	1.998		1.9		
		$I_{OH} = -20  \mu A$	4.5 V	4.4	4.499		4.4		
VOH VI = VIH or VIL	VI = VIH or VIL		6 V	5.9	5.999		5.9		V
	$I_{OH} = -4 \text{ mA}$	4.5 V	3.98	4.3		3.84			
		$I_{OH} = -5.2 \text{ mA}$	6 V	5.48	5.8		5.34		
			2 V		0.002	0.1		0.1	
		I <sub>OL</sub> = 20 μA	4.5 V		0.001	0.1		0.1	
$V_{OL}$	$V_I = V_{IH}$ or $V_{IL}$		6 V		0.001	0.1		0.1	V
		$I_{OL} = 4 \text{ mA}$	4.5 V		0.17	0.26		0.33	
		$I_{OL} = 5.2 \text{ mA}$	6 V		0.15	0.26		0.33	
ΙĮ	$V_I = V_{CC}$ or 0	·	6 V		±0.1	±100	=	±1000	nA
Icc	$V_I = V_{CC}$ or 0,	I <sub>O</sub> = 0	6 V			8		80	μΑ
C <sub>i</sub>			2 V to 6 V	·	3	10		10	pF

NOTE 3: All unused inputs of the device must be held at V<sub>CC</sub> or GND to ensure proper device operation. Refer to the TI application report, Implications of Slow or Floating CMOS Inputs, literature number SCBA004.

## SN74HC166A-EP 8-BIT PARALLEL-LOAD SHIFT REGISTER

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# timing requirements over recommended operating free-air temperature range (unless otherwise noted)

			1.,	T <sub>A</sub> =	25°C			
			VCC	MIN	MAX	MIN	MAX	UNIT
			2 V		6		5	
fclock	Clock frequency		4.5 V		31		25	MHz
			6 V		36		29	
			2 V	100		125		
		CLR low	4.5 V	20		25		
	B		6 V	17		21		
t <sub>W</sub>	Pulse duration		2 V	80		100		ns
		CLK high or low	4.5 V	16		20		
			6 V	14		17		
			2 V	145		180		
		SH/LD high before CLK↑	4.5 V	29		36		
			6 V	25		31		
			2 V	80		100		
		SER before CLK↑	4.5 V	16		20		
t <sub>su</sub> Setup time		6 V	14		17			
		2 V	100		125			
	CLK INH low before CLK↑	4.5 V	20		25		ns	
			6 V	17		21		
			2 V	80		100		
		Data before CLK↑	4.5 V	16		20		
			6 V	14		17		
			2 V	40		50		
		CLR inactive before CLK↑	4.5 V	8		10		
			6 V	7		9		
			2 V	0		0		
		SH/LD high after CLK↑	4.5 V	0		0		
			6 V	0		0		
			2 V	5		5		
		SER after CLK↑	4.5 V	5		5		
			6 V	5		5		
th	Hold time		2 V	0		0		ns
		CLK INH high after CLK↑	4.5 V	0		0		
		<b>5</b> and 2 <b>2</b> and	6 V	0		0		- - -
			2 V	5		5		
		Data after CLK↑	4.5 V	5		5		
			6 V	5		5		



## SN74HC166A-EP 8-BIT PARALLEL-LOAD SHIFT REGISTER

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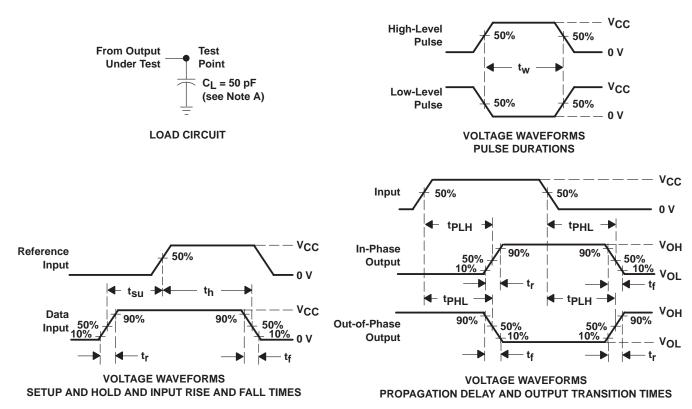
## switching characteristics over recommended operating free-air temperature range, $C_L$ = 50 pF (unless otherwise noted) (see Figure 1)

DADAMETER	FROM	то	,,	T,	<b>Վ = 25°</b> C	;	BAIN!	MAY	
PARAMETER	(INPUT)	(OUTPUT)	VCC	MIN	TYP	MAX	MIN	MAX	UNIT
			2 V	6	11		5		
fmax			4.5 V	31	36		25		MHz
			6 V	36	45		29		
			2 V		62	120		150	
t <sub>PHL</sub>	CLR	Q <sub>H</sub>	4.5 V		18	24		30	ns
			6 V		13	20		26	
			2 V		75	150		190	
<sup>t</sup> pd	CLK	QH	4.5 V		15	30		38	ns
'			6 V		13	26		32	
			2 V		38	75		95	
t <sub>t</sub>		Any	4.5 V		8	15		19	ns
			6 V		6	13		16	

## operating characteristics, $T_A = 25^{\circ}C$

	PARAMETER	TEST CONDITIONS	TYP	UNIT
C <sub>pd</sub>	Power dissipation capacitance	No load	50	pF

#### PARAMETER MEASUREMENT INFORMATION



NOTES: A. C<sub>I</sub> includes probe and test-fixture capacitance.

- B. Phase relationships between waveforms were chosen arbitrarily. All input pulses are supplied by generators having the following characteristics: PRR  $\leq$  1 MHz,  $Z_O = 50 \ \Omega$ ,  $t_f = 6 \ ns$ ,  $t_f = 6 \ ns$ .
- C. For clock inputs,  $f_{\text{max}}$  is measured when the input duty cycle is 50%.
- D. The outputs are measured one at a time with one input transition per measurement.
- E. tpLH and tpHL are the same as tpd.

Figure 1. Load Circuit and Voltage Waveforms



#### PACKAGE OPTION ADDENDUM

10-Dec-2020

#### PACKAGING INFORMATION

www.ti.com

Orderable Device	Status (1)	Package Type	Package Drawing	Pins	Package Qty	Eco Plan	Lead finish/ Ball material	MSL Peak Temp	Op Temp (°C)	Device Marking (4/5)	Samples
SN74HC166AIDREP	ACTIVE	SOIC	D	16	2500	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-40 to 85	SHC166IEP	Samples
V62/04690-01XE	ACTIVE	SOIC	D	16	2500	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-40 to 85	SHC166IEP	Samples

(1) The marketing status values are defined as follows:

**ACTIVE:** Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

PREVIEW: Device has been announced but is not in production. Samples may or may not be available.

**OBSOLETE:** TI has discontinued the production of the device.

(2) RoHS: TI defines "RoHS" to mean semiconductor products that are compliant with the current EU RoHS requirements for all 10 RoHS substances, including the requirement that RoHS substance do not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, "RoHS" products are suitable for use in specified lead-free processes. TI may reference these types of products as "Pb-Free".

RoHS Exempt: TI defines "RoHS Exempt" to mean products that contain lead but are compliant with EU RoHS pursuant to a specific EU RoHS exemption.

Green: TI defines "Green" to mean the content of Chlorine (CI) and Bromine (Br) based flame retardants meet JS709B low halogen requirements of <=1000ppm threshold. Antimony trioxide based flame retardants must also meet the <=1000ppm threshold requirement.

- (3) MSL, Peak Temp. The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.
- (4) There may be additional marking, which relates to the logo, the lot trace code information, or the environmental category on the device.
- (5) Multiple Device Markings will be inside parentheses. Only one Device Marking contained in parentheses and separated by a "~" will appear on a device. If a line is indented then it is a continuation of the previous line and the two combined represent the entire Device Marking for that device.
- (6) Lead finish/Ball material Orderable Devices may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead finish/Ball material values may wrap to two lines if the finish value exceeds the maximum column width.

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### **PACKAGE OPTION ADDENDUM**

10-Dec-2020

#### OTHER QUALIFIED VERSIONS OF SN74HC166A-EP:

Automotive: SN74HC166A-Q1

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NOTE: Qualified Version Definitions:

• Automotive - Q100 devices qualified for high-reliability automotive applications targeting zero defects

## PACKAGE MATERIALS INFORMATION

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#### TAPE AND REEL INFORMATION





	Dimension designed to accommodate the component width
B0	Dimension designed to accommodate the component length
K0	Dimension designed to accommodate the component thickness
W	Overall width of the carrier tape
P1	Pitch between successive cavity centers

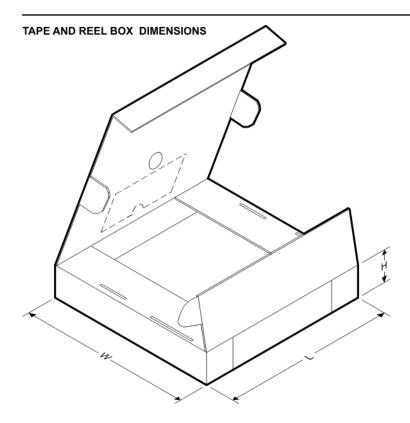
#### QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE



#### \*All dimensions are nominal

Device	Package Type	Package Drawing			Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
SN74HC166AIDREP	SOIC	D	16	2500	330.0	16.4	6.5	10.3	2.1	8.0	16.0	Q1

www.ti.com 3-Aug-2021



#### \*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)
SN74HC166AIDREP	SOIC	D	16	2500	340.5	336.1	32.0

## D (R-PDS0-G16)

#### PLASTIC SMALL OUTLINE



NOTES:

- A. All linear dimensions are in inches (millimeters).
- B. This drawing is subject to change without notice.
- Body length does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not exceed 0.006 (0,15) each side.
- Body width does not include interlead flash. Interlead flash shall not exceed 0.017 (0,43) each side.
- E. Reference JEDEC MS-012 variation AC.



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